





EH36 25 ET T TS -83.333M

Series — RoHS Compliant (Pb-free) 3.3V 4 Pad 3.2mm x 5mm Ceramic SMD LVCMOS High Frequency Oscillator

Operating Temperature Range – -40°C to +85°C

Nominal Frequency 83.333MHz

Pin 1 Connection
Tri-State (High Impedance)

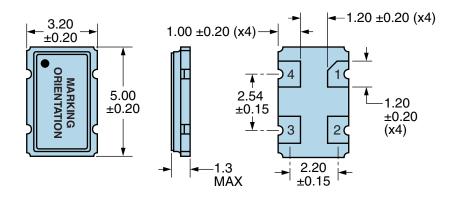
- Duty Cycle 50 ±5(%)

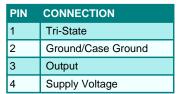
#25ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, 1st Year Aging at 25°C, Shock, and Vibration) #25ppm/year Maximum #25ppm/year Maxi	ELECTRICAL SPECIFICATIONS		
Aging at 25°C Aging at 25°C Aging at 25°C ±5ppm/year Maximum Operating Temperature Range -40°C to +85°C Supply Voltage 3.3Vdc ±0.3Vdc Input Current 35mA Maximum (No Load) Output Voltage Logic High (Voh) 2.7Vdc Minimum (IOH = -8mA) Output Voltage Logic Low (Vol) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle Load Drive Capability Output Logic Type Pin 1 Connection Tri-State Input Voltage (Vih and Vil) Tri-State Input Voltage (Vih and Vil) Absolute Clock Jitter ±250pSec Maximum, ±10pSec Typical Statt Up Time 10mSec Maximum 1-40°C to +85°C 2.7Vdc Minimum (IOH = -8mA) 0.5Vdc Maximum (IOE = +8mA) 1.5Vdc Maximum (IOE = -8mA) 1.5Vdc Maximum to 80% of waveform) 1.5Vdc Maximum to 80% of waveform) 1.5Vdc Maximum to 90% of waveform) 1.5	Nominal Frequency	83.333MHz	
Operating Temperature Range -40°C to +85°C Supply Voltage 3.3Vdc ±0.3Vdc Input Current 35mA Maximum (No Load) Output Voltage Logic High (Voh) 2.7Vdc Minimum (IOH = -8mA) Output Voltage Logic Low (Vol) 0.5Vdc Maximum (IOL = +8mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±5(%) (Measured at 50% of waveform) Load Drive Capability 15pF Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical Start Up Time 10mSec Maximum	Frequency Tolerance/Stability	Operating Temperature Range, Supply Voltage Change, Output Load Change, 1st Year Aging at 25°C,	
Supply Voltage 3.3Vdc ±0.3Vdc Input Current 35mA Maximum (No Load) Output Voltage Logic High (Voh) 2.7Vdc Minimum (IOH = -8mA) Output Voltage Logic Low (Vol) 0.5Vdc Maximum (IOL = +8mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±5(%) (Measured at 50% of waveform) Load Drive Capability 15pF Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Aging at 25°C	±5ppm/year Maximum	
Input Current 35mA Maximum (No Load) Output Voltage Logic High (Voh) 2.7Vdc Minimum (IOH = -8mA) Output Voltage Logic Low (Vol) 0.5Vdc Maximum (IOL = +8mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±5(%) (Measured at 50% of waveform) Load Drive Capability 15pF Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter 250pSec Maximum, ±100pSec Typical 5tart Up Time 10mSec Maximum 10mSec Maximum	Operating Temperature Range	-40°C to +85°C	
Output Voltage Logic High (Voh) 2.7Vdc Minimum (IOH = -8mA) Output Voltage Logic Low (Vol) 0.5Vdc Maximum (IOL = +8mA) Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±5(%) (Measured at 50% of waveform) Load Drive Capability 15pF Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Supply Voltage	3.3Vdc ±0.3Vdc	
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Rise/Fall Time 4nSec Maximum (Measured at 20% to 80% of waveform) Duty Cycle 50 ±5(%) (Measured at 50% of waveform) Load Drive Capability 15pF Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Output Voltage Logic High (Voh)	2.7Vdc Minimum (IOH = -8mA)	
Duty Cycle 50 ±5(%) (Measured at 50% of waveform) Load Drive Capability 15pF Maximum Output Logic Type CMOS Pin 1 Connection Tri-State (High Impedance) Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Output Voltage Logic Low (Vol)	0.5Vdc Maximum (IOL = +8mA)	
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Tri-State Input Voltage (Vih and Vil) 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output, No Connect to enable output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Output Logic Type	CMOS	
output. Absolute Clock Jitter ±250pSec Maximum, ±100pSec Typical One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Pin 1 Connection	Tri-State (High Impedance)	
One Sigma Clock Period Jitter ±50pSec Maximum, ±40pSec Typical Start Up Time 10mSec Maximum	Tri-State Input Voltage (Vih and Vil)		
Start Up Time 10mSec Maximum	Absolute Clock Jitter	±250pSec Maximum, ±100pSec Typical	
	One Sigma Clock Period Jitter	±50pSec Maximum, ±40pSec Typical	
Storage Temperature Range -55°C to +125°C	Start Up Time	10mSec Maximum	
	Storage Temperature Range	-55°C to +125°C	

ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
Fine Leak Test	MIL-STD-883, Method 1014, Condition A	
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	
Mechanical Shock	MIL-STD-202, Method 213, Condition C	
Resistance to Soldering Heat	MIL-STD-202, Method 210	
Resistance to Solvents	MIL-STD-202, Method 215	
Solderability	MIL-STD-883, Method 2003	
Temperature Cycling	MIL-STD-883, MEthod 1010	
Vibration	MIL-STD-883, Method 2007, Condition A	



MECHANICAL DIMENSIONS (all dimensions in millimeters)

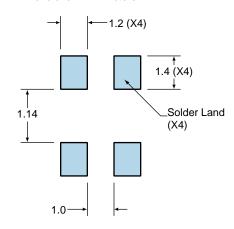




LINE	MARKING
1	E83.333 E=Ecliptek Designator

Suggested Solder Pad Layout

All Dimensions in Millimeters



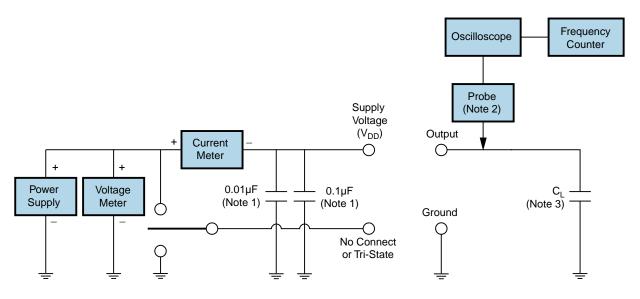
All Tolerances are ±0.1



OUTPUT WAVEFORM & TIMING DIAGRAM



Test Circuit for CMOS Output



- Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.
- Note 3: Capacitance value \dot{C}_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods



High Temperature Infrared/Convection

T _s MAX to T _∟ (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	150°C
- Temperature Typical (T _s TYP)	175°C
- Temperature Maximum (T _S MAX)	200°C
- Time (t _s MIN)	60 - 180 Seconds
Ramp-up Rate (T _L to T _P)	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T _P)	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T _P Target)	250°C +0/-5°C
Time within 5°C of actual peak (tp)	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1



Recommended Solder Reflow Methods



Low Temperature Infrared/Convection 240°C

T _S MAX to T _L (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (T _s MIN)	N/A
- Temperature Typical (T _s TYP)	150°C
- Temperature Maximum (T _s MAX)	N/A
- Time (t _s MIN)	60 - 120 Seconds
Ramp-up Rate (T _L to T _P)	5°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T _P)	240°C Maximum
Target Peak Temperature (T _P Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (tp)	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.